



Integrated Device Technology, Inc.

# HIGH SPEED BiCMOS 10-BIT MEMORY DRIVERS

**ADVANCE  
INFORMATION**  
IDT54/74FBT2827A/B  
IDT54/74FBT2828A/B

## FEATURES

- IDT54/74FBT2827A/2828A is equivalent to 54/74BCT2827A/2828A
- **IDT54/74FBT2827B/2828B is 30% faster than BCT**
- 25Ω output resistors reduce overshoot and undershoot when driving MOS RAMs
- Significant reduction in ground bounce from standard CMOS devices
- TTL compatible input and output levels
- Higher static VOH for improved noise immunity and reduced system power dissipation
- Low power in all three states
- ±10% power supply for both military and commercial grades
- JEDEC standard pinout for DIP, SOIC and LCC packages
- Military product compliant to MIL-STD-883, Class B

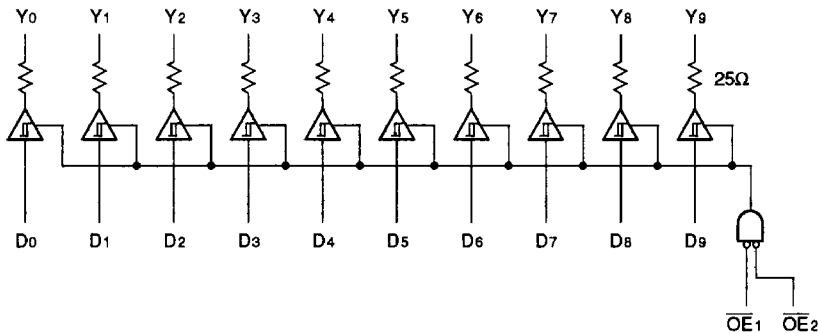
## DESCRIPTION

The FBT series of BiCMOS Memory Drivers are built using advanced BiCEMOS™, a dual metal BiCMOS technology. This technology is designed to supply the highest device speeds while maintaining CMOS power levels.

The IDT54/74FBT2827A/B and IDT54/74FBT2828A/B are 3-state 10-bit buffers where each output is terminated with a 25Ω series resistor. The output buffers are enabled when the two Active-LOW output enable pins are logic LOW.

The FBT series of memory line drivers are ideal for use in designs needed to drive large capacitive loads, with low static (DC) current loading. All data inputs have a 200mV typical input hysteresis for improved noise rejection. They are also designed for rail-to-rail output switching. This higher output level in the high state will result in significant reduction in overall system power dissipation.

## FUNCTIONAL BLOCK DIAGRAM



2516 drw 01

## PRODUCT SELECTOR GUIDE

	10-Bit Memory Driver
Non-inverting	IDT 54/74FBT2827A/B
Inverting	IDT 54/74FBT2828A/B

2516 tbi 01

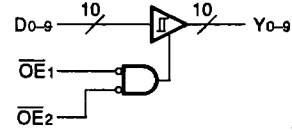
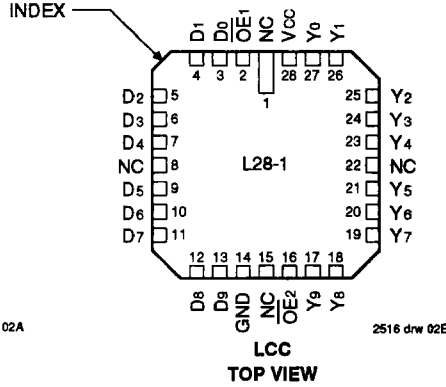
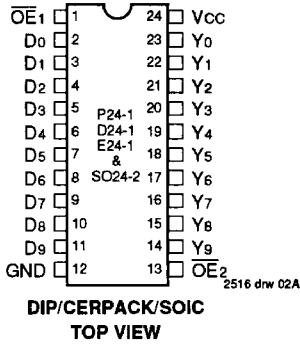
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**MILITARY AND COMMERCIAL TEMPERATURE RANGES**

**APRIL 1992**

**PIN CONFIGURATIONS**

**LOGIC SYMBOL**



2516 drw 03

**PIN DESCRIPTION**

Name	I/O	Description
OE1 OE2	I	When both are LOW, the outputs are enabled. When either one or both are HIGH the outputs are High Z.
Di	I	10-bit data input.
Yi	O	10-bit data output.

2516 tbl 02

**FUNCTION TABLES**

**IDT54/74FBT2827A/B (Non-Inverting)<sup>(1)</sup>**

Inputs			Output	Function
OE1	OE2	Di	Yi	
L	L	L	L	Transparent
L	L	H	H	
H	X	X	Z	3-State
X	H	X	Z	

**NOTE:**  
1. H = HIGH, L = LOW, X = Don't Care, Z = High Impedance

2516 tbl 03

**IDT54/74FBT2828A/B (Inverting)<sup>(1)</sup>**

Inputs			Output	Function
OE1	OE2	Di	Yi	
L	L	L	H	Transparent
L	L	H	L	
H	X	X	Z	3-State
X	H	X	Z	

**NOTE:**  
1. H = HIGH, L = LOW, X = Don't Care, Z = High Impedance

2516 tbl 04



**ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>**

Symbol	Rating	Com'l.	Mil.	Unit
V <sub>TERM</sub> <sup>(2)</sup>	Terminal Voltage with Respect to GND	-0.5 to +7.0	-0.5 to +7.0	V
V <sub>TERM</sub> <sup>(3)</sup>	Terminal Voltage with Respect to GND	-0.5 to V <sub>CC</sub>	-0.5 to V <sub>CC</sub>	V
T <sub>A</sub>	Operating Temperature	0 to +70	-55 to +125	°C
T <sub>BIAS</sub>	Temperature Under Bias	-55 to +125	-65 to +135	°C
T <sub>STG</sub>	Storage Temperature	-55 to +125	-65 to +150	°C
P <sub>T</sub>	Power Dissipation	0.5	0.5	W
I <sub>OUT</sub>	DC Output Current	120	120	mA

**NOTES:** 2516 tbl 06

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed V<sub>CC</sub> by +0.5V unless otherwise noted.
- Input and V<sub>CC</sub> terminals only.
- Outputs and I/O terminals only.

**CAPACITANCE** (T<sub>A</sub> = +25°C, f = 1.0MHz)

Symbol	Parameter <sup>(1)</sup>	Condition	Typ.	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 0V	6	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 0V	8	pF

**NOTE:** 2516 tbl 07  
1. This parameter is measured at characterization but not tested.

**DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE**

Following Conditions Apply Unless Otherwise Specified: V<sub>LC</sub> = 0.2V; V<sub>HC</sub> = V<sub>CC</sub> - 0.2V  
Commercial: T<sub>A</sub> = 0°C to +70°C, V<sub>CC</sub> = 5.0V ± 10%; Military: T<sub>A</sub> = -55°C to +125°C, V<sub>CC</sub> = 5.0V ± 10%

Symbol	Parameter	Test Condition <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit
V <sub>IH</sub>	Input HIGH Level	Guaranteed Logic High Level		2.0	—	—	V
V <sub>IL</sub>	Input LOW Level	Guaranteed Logic Low Level		—	—	0.8	V
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> = Max.	V <sub>I</sub> = 2.7V	—	—	10	μA
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> = Max.	V <sub>I</sub> = 0.5V	—	—	-10	μA
I <sub>OZH</sub>	High Impedance	V <sub>CC</sub> = Max.	V <sub>O</sub> = 2.7V	—	—	50	μA
I <sub>OZL</sub>	Output Current		V <sub>O</sub> = 0.5V	—	—	-50	
I <sub>I</sub>	Input HIGH Current	V <sub>CC</sub> = Max., V <sub>I</sub> = 5.5V		—	—	100	μA
V <sub>IK</sub>	Clamp Diode Voltage	V <sub>CC</sub> = Min., I <sub>N</sub> = -18mA		—	-0.7	-1.2	V
I <sub>ODH</sub>	Output Drive Current	V <sub>CC</sub> = Min., V <sub>O</sub> = 2.25V		-35	—	—	mA
I <sub>ODL</sub>	Output Drive Current	V <sub>CC</sub> = Min., V <sub>O</sub> = 2.25V		50	—	—	mA
I <sub>OS</sub>	Short Circuit Current	V <sub>CC</sub> = Max., V <sub>O</sub> = GND <sup>(3)</sup>		-60	—	-225	mA
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min. V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -300μA <sup>(4)</sup>	V <sub>HC</sub>	V <sub>CC</sub>	—	V
			I <sub>OH</sub> = -1mA	2.4	3.3	—	
			I <sub>OH</sub> = -12mA	2.0	3.2	—	
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min. V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 300μA <sup>(4)</sup>	—	GND	V <sub>LC</sub>	V
			I <sub>OL</sub> = 1mA	—	0.1	0.5	
			I <sub>OL</sub> = 12mA	—	0.35	0.8	
				—	—	—	
V <sub>H</sub>	Input Hysteresis	—		—	200	—	mV
I <sub>CCH</sub> I <sub>CCZ</sub> I <sub>CCL</sub>	Quiescent Power Supply Current	V <sub>CC</sub> = Max. V <sub>IN</sub> = GND or V <sub>CC</sub>		—	0.2	1.5	mA

- NOTES:** 2516 tbl 05
- For condition shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
  - Typical values are at V<sub>CC</sub> = 5.0V, +25°C ambient and maximum loading.
  - Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.
  - This condition is guaranteed but not tested.

**POWER SUPPLY CHARACTERISTICS**

Symbol	Parameter	Test Condition <sup>(1)</sup>	Min.	Typ.	Max.	Unit	
$\Delta I_{CC}$	Quiescent Power Supply Current (Inputs TTL HIGH)	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$	—	0.5	2.0	mA	
$I_{CCD}$	Dynamic Power Supply Current <sup>(4)</sup>	$V_{CC} = \text{Max.}$ , Outputs Open $\overline{OE}_1 = \overline{OE}_2 = \text{GND}$ One Input Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	0.15	0.25 mA/ MHz	
$I_C$	Total Power Supply Current <sup>(6)</sup>	$V_{CC} = \text{Max.}$ , Outputs Open $f_i = 10\text{MHz}$ , 50% Duty Cycle $\overline{OE}_1 = \overline{OE}_2 = \text{GND}$ One Bit Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	1.7	4.0	mA
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	2.0	5.0	
		$V_{CC} = \text{Max.}$ , Outputs Open $f_i = 2.5\text{MHz}$ , 50% Duty Cycle $\overline{OE}_1 = \overline{OE}_2 = \text{GND}$ Ten Bits Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	4.0	7.8 <sup>(5)</sup>	
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	6.5	17.8 <sup>(5)</sup>	

**NOTES:**

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- For condition shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at  $V_{CC} = 5.0V$ ,  $+25^\circ\text{C}$  ambient.
- Per TTL driven input ( $V_{IN} = 3.4V$ ); all other inputs at  $V_{CC}$  or  $\text{GND}$ .
- This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
- Values for these conditions are examples of the  $I_{CC}$  formula. These limits are guaranteed but not tested.
- $I_C = I_{\text{QUIESCENT}} + I_{\text{DYNAMIC}}$   
 $I_C = I_{CC} + \Delta I_{CC} \text{DH} + I_{CCD} (f_{CP}/2 + f_i N_i)$   
 $I_{CC} = \text{Quiescent Current}$   
 $\Delta I_{CC} = \text{Quiescent Current}$   
 $\text{DH} = \text{Duty Cycle for a TTL High Input } (V_{IN} = 3.4V)$   
 $N_T = \text{Number of TTL Inputs at DH}$   
 $I_{CCD} = \text{Dynamic Current caused by an Input Transition Pair (HLH or LHL)}$   
 $f_{CP} = \text{Clock Frequency for Register Devices (Zero for Non-Register Devices)}$   
 $f_i = \text{Input Frequency}$   
 $N_i = \text{Number of Inputs at } f_i$   
 All currents are in milliamps and all frequencies are in MHz.

**SWITCHING CHARACTERISTICS OVER OPERATING RANGE**

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Symbol	Parameter	FBT2827A				FBT2827B			
		Commercial		Military		Commercial		Military	
		Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.
$t_{PHL}$ $t_{PLH}$	Prop Delay, $D_i$ to $Y_i$	1.5	7.0	1.5	7.5	1.5	5.0	1.5	6.5
$t_{PZH}$ $t_{PZL}$	Output Enable Time $\overline{OE}$ to $Y_i$	1.5	13.0	1.5	14	1.5	8.0	1.5	9.0
$t_{PHZ}$ $t_{PLZ}$	Output Disable Time $\overline{OE}$ to $Y_i$	1.5	13.0	1.5	14	1.5	7.0	1.5	8.0

Symbol	Parameter	FBT2828A				FBT2828B			
		Commercial		Military		Commercial		Military	
		Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.
$t_{PHL}$ $t_{PLH}$	Prop Delay, $D_i$ to $Y_i$	1.5	8.0	1.5	8.5	1.5	5.5	1.5	6.5
$t_{PZH}$ $t_{PZL}$	Output Enable Time $\overline{OE}$ to $Y_i$	1.5	12.0	1.5	13.0	1.5	8.0	1.5	9.0
$t_{PHZ}$ $t_{PLZ}$	Output Disable Time $\overline{OE}$ to $Y_i$	1.5	14.0	1.5	15.0	1.5	7.0	1.5	8.0

**NOTES:**

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- See test circuit and waveforms.
- Minimum limits are guaranteed but not tested on Propagation Delays.
- These parameters are guaranteed but not tested.